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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re the Application of: **FUKASAWA, et al.**

Group Art Unit: **2814**

Serial No.: **09/029,608**

Examiner: **D. Graybill**

Filed: **May 15, 1998**

P.T.O. Confirmation No.: 6285

For: **METHOD AND MOLD FOR MANUFACTURING SEMICONDUCTOR DEVICE,
SEMICONDUCTOR**

INFORMATION DISCLOSURE STATEMENT
PURSUANT TO 37 CFR 1.97(b)

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

July 28, 2003

Sir:

The attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached Form PTO-1449. One copy of each of these documents is attached along with an Office Action mailed June 17, 2003 of corresponding Japanese Patent Application No. 9-181132 and a European Search Report dated June 3, 2003. The remaining references were cited in Office Actions dated June 18, 2003 and June 2, 2003 for related U.S. Serial No. 09/766,656 and related U.S. Serial No. 09/635,124, respectively.

No fee or certification is required in connection with this Information Disclosure Statement, since it is being submitted prior to the issuance of a first official action on the merits following the **Request for Continued Examination (RCE)** in the above-identified patent application.

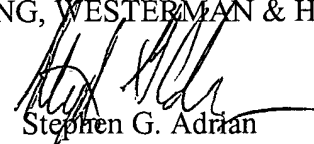
The above information is presented so that the Patent and Trademark Office can, in the first instance, determine any materiality thereof to the claimed invention. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the

documents cited in the attached Form PTO-1449 be made of record therein and appear on the first page of any patent to issue therefrom.

The Commissioner is authorized to charge our Deposit Account No. 01-2340 for any fee which is deemed by the Patent and Trademark Office to be required to effect consideration of this statement.

Respectfully submitted,

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PATENT TRADEMARK OFFICE

Enclosures: PTO-1449; Office Action dated June 17, 2003;
European Search Report dated June 3, 2003
and references (35)



INFORMATION DISCLOSURE CITATION PTO-1449	Docket No. 980233	Serial No. 09/029,608
	Applicant(s): FUKASAWA, et al.	
	Filing Date: May 15, 1998	Group Art Unit: 2814

U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Name	Date	Class	Subclass	Filing Date (If appropriate)
_____	AA	5,307,561	Feigenbaum et al.	5/1994		
_____	AB	5,309,021	Shimamoto et al.	5/1994		
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_____	BB	8-255868 ✓	10/1/1996	Japan	Abstract
_____	BC	5-82717 ✓	4/2/1993	Japan	Abstract
_____	BD	EP 0 704 896 A2 ✓	4/3/1996	Europe	
_____	BE	EP 0 684 641 A2 ✓	11/29/95	Europe	
_____	BF	EP 0 689 245 A2 ✓	12/27/1995	Europe	
_____	BG	63-308329 ✓	12/15/1988	Japan	Abstract
_____	BH	5-55278 ✓	3/5/1993	Japan	Abstract

OTHER DOCUMENTS

_____	BI	Translation of JP8-64725
_____	BJ	Translation of JP7-45649
Examiner		Date Considered